	N	74ACT TAL BUS TRANSC VITH 3-STATE OUT 2957, JULY 1987 – REVISED A
<ul> <li>Local Bus-Latch Capability</li> </ul>		
Inputs Are TTL-Voltage Compatible	(10	P VIEW)
<ul> <li>Flow-Through Architecture Optimizes</li> </ul>	A1 🛛 1	U 24 GAB
PCB Layout	A2 🛛 2	23 B1
<ul> <li>Center-Pin V<sub>CC</sub> and GND Configurations</li> </ul>	АЗ 🛛 З	22 🛛 B2
Minimize High-Speed Switching Noise	A4 🛛 4	21 🛛 B3
<ul> <li>EPIC<sup>™</sup> (Enhanced-Performance Implanted</li> </ul>	GND 5	<sup>20</sup> B4
CMOS) 1-µm Process	GND [] 6	19 🛛 V <sub>CC</sub>
• 500-mA Typical Latch-Up Immunity		18 V <sub>CC</sub>
at 125°C		17 B5
• Package Options Include Plastic Small-	A5 4 9	16 B6
Outline Packages and Standard Plastic	A6 [ 10	P 07
300-mil DIPs	A7 🛛 11	
	A8 🛛 12	<sup>13</sup> GBA

### description

The 74ACT11623 is designed for asynchronous two-way communication between data buses. The control function implementation allows for maximum flexibility in timing.

The device allows data transmission from the A bus to the B bus or from the B bus to the A bus depending upon the logic levels at the enable inputs ( $\overline{G}BA$  and GAB). The enable inputs can be used to disable the device so that the buses are effectively isolated.

The dual-enable configuration gives these devices the capability to store data by simultaneous enabling of  $\overline{G}BA$  and GAB. Each output reinforces its input in this transceiver configuration. Thus, when both control inputs are enabled and all other data sources to the two sets of bus lines are at high impedance, both sets of bus lines (16 in all) will remain at their last states. The 8-bit codes appearing on the two sets of buses will be identical for the 74ACT11623.

The 74ACT11623 is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

ENABL	E INPUTS	OPERATION				
GBA	GAB	OPERATION				
L	L	B data to A bus				
Н	Н	A data to B bus				
Н	L	Isolation				
1	н	B data to A bus,				
E 11	11	A data to B bus				

#### FUNCTION TABLE

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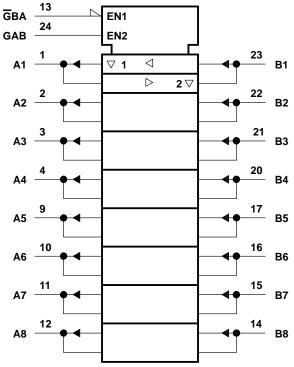
T11623

APRIL 1993

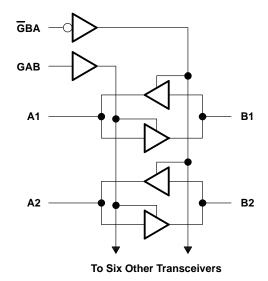
# 74ACT11623 OCTAL BUS TRANSCEIVER WITH 3-STATE OUTPUTS

SCAS059A - D2957, JULY 1987 - REVISED APRIL 1993

### logic symbol<sup>†</sup>



logic diagram (positive logic)



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	$\dots \dots -0.5$ V to V <sub>CC</sub> + 0.5 V
Output voltage range, V <sub>O</sub> (see Note 1)	$-0.5$ V to V <sub>CC</sub> + 0.5 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	$\dots \dots \pm 20 \text{ mA}$
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	$\dots \dots \pm 50 \text{ mA}$
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	$\dots \dots \pm 50 \text{ mA}$
Continuous current through V <sub>CC</sub> or GND	$\dots \dots \pm 200 \text{ mA}$
Storage temperature range	–65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



### recommended operating conditions

		MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	V
VIH	High-level input voltage	2		V
VIL	Low-level input voltage		0.8	V
VI	Input voltage	0	VCC	V
VO	Output voltage	0	VCC	V
ЮН	High-level output current		-24	mA
IOL	Low-level output current		24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V
TA	Operating free-air temperature	- 40	85	°C

### electrical characteristics over recommended operating free-air temperature range

PARAMETER		TEST CONDITIONS	Vcc	T <sub>A</sub> = 25°C			MIN	МАХ	UNIT
		TEST CONDITIONS		MIN	TYP	MAX	MIIN	MAX	UNIT
		I <sub>OH</sub> = - 50 μA	4.5 V	4.4			4.4		
			5.5 V	5.4			5.4		
∨он			4.5 V	3.94			3.8		V
		I <sub>OH</sub> = – 24 mA	5.5 V	4.94			4.8		
		$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
		I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1	V
		$OL = 30 \ \mu A$	5.5 V			0.1		0.1	
VOL		I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.44	
			5.5 V			0.36		0.44	
		$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
IOZ A or B ports‡		$V_{O} = V_{CC}$ or GND	5.5 V			± 0.5		±5	μA
Ц	GBA or GAB	$V_I = V_{CC}$ or GND	5.5 V			± 0.1		± 1	μA
ICC		$V_{I} = V_{CC} \text{ or } GND,  I_{O} = 0$	5.5 V			4		40	μA
∆I <sub>CC</sub> §		One input at 3.4 V, Other inputs at GND or $V_{\mbox{CC}}$	5.5 V			0.9		1	mA
Ci	GBA or GAB	$V_{I} = V_{CC} \text{ or } GND$	5 V		4				pF
C <sub>io</sub>	A or B ports	$V_{O} = V_{CC}$ or GND	5 V		20				pF

Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.
 For I/O ports, the parameter I<sub>OZ</sub> includes the input leakage.

§ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V<sub>CC</sub>.



# 74ACT11623 **OCTAL BUS TRANSCEIVER** WITH 3-STATE OUTPUTS SCAS059A – D2957, JULY 1987 – REVISED APRIL 1993

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Т	ק = 25°C	;	MIN	МАХ	UNIT
FARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX			UNIT
<sup>t</sup> PLH	A or B	B or A	1.5	6	7.5	1.5	8.5	ns
<sup>t</sup> PHL	A OF B	BOR	1.5	5.5	7.2	1.5	7.9	115
<sup>t</sup> PZH	Gва	A	1.5	6.9	8.6	1.5	9.7	
<sup>t</sup> PZL			1.5	6.9	9	1.5	10	ns
<sup>t</sup> PHZ	Gва	А	1.5	8.1	10	1.5	10.9	
<sup>t</sup> PLZ		ζ.	1.5	8.5	10.5	1.5	11.5	ns
<sup>t</sup> PZH	GAB	В	1.5	7.7	9.3	1.5	10.7	ns
t <sub>PZL</sub>	GAB		1.5	7.7	9.7	1.5	10.9	115
<sup>t</sup> PHZ	GAB	В	1.5	7.1	8.8	1.5	9.5	ns
<sup>t</sup> PLZ		ם	1.5	7.3	9.2	1.5	10	115

## operating characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

PARAMETER		TEST CON	ТҮР	UNIT		
C <sub>pd</sub>	Dower discipation conscitutes per transciver	Outputs enabled	$C_1 = 50  \text{pF},$	f = 1 MHz	41	<b>5</b> 5
	Power dissipation capacitance per transceiver	Outputs disabled	CL = 50 pr,		8	р⊢



 $2 \times V_{CC}$ TEST **S**1 0 **S1** tPLH/tPHL Open **500** Ω O Open From Output tPLZ/tPZL  $2 \times V_{CC}$  $\wedge \wedge \wedge$ Under Test  $\circ$  gnd tPHZ/tPZH GND  $C_L = 50 \text{ pF}$ ≶ **500** Ω (see Note A) LOAD CIRCUIT Output 3 V Control 1.5 V 1.5 V (low-level 0 V enabling) t<sub>PZL</sub> 3 V tPLZ -Input Output ≈ Vcc 1.5 V 1.5 V (see Note B) Waveform 1 50% V<sub>CC</sub> 20% V<sub>CC</sub> 0 V S1 at  $2 \times V_{CC}$ Vol (see Note C) <sup>t</sup>PLH tPHZ -<sup>t</sup>PHL tPZH -Output Vон ۷он 50% V<sub>CC</sub> Waveform 2 80% VCC 50% V<sub>CC</sub> 50% V<sub>CC</sub> Output S1 at GND Vol ≈ 0 V (see Note C) **VOLTAGE WAVEFORMS VOLTAGE WAVEFORMS** 

### PARAMETER MEASUREMENT INFORMATION

- NOTES: A. CL includes probe and jig capacitance.
  - B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>r</sub> = 3 ns, t<sub>f</sub> = 3 ns. C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
    - Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - D. The outputs are measured one at a time with one input transition per measurement.

#### Figure 1. Load Circuit and Voltage Waveforms



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